

## **Abstract**

A method for enabling test vectors to be generated for a customer designed integrated circuit (16) having an embedded vendor circuit (12) is disclosed. The embedded vendor circuit (12) has a proprietary circuit (18) and a nonproprietary circuit (20). At least one pseudo input is defined (62) to represent a portion of the nonproprietary circuit (20) to emulate the nonproprietary circuit output. An output node (31) of the embedded vendor circuit (12) to which an input of the customer designed circuit (14) is connectable is identified (64). A test netlist is created (66) which represents circuitry that produces output states at the output node (31) which would be generated by the embedded vendor circuit thereat (12). The test netlist includes at least one pseudo input and the output node, without including a full netlist of either the proprietary or nonproprietary circuits, and can be used to generate (72) scan test vectors for the customer designed integrated circuit (14) by the automatic test vector generating software program.